

An educational environment for digital testing : hardware, tools, and web-based runtime platform

Jutman, Artur; Raik, Jaan; Ubar, Raimund-Johannes; Vislogubov, Vladislav Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 412-419 : ill https://www.researchgate.net/profile/Artur-Jutman/publication/220880167_An_Educational_Environment_for_Digital_Testing_Hardware_Tools_and_Web-Based_Runtime_Platform/links/02e7e53c3c71b0b2a7000000/An-Educational-Environment-for-Digital-Testing-Hardware-Tools-and-Web-Based-Runtime-Platform.pdf

Defect-oriented test- and layout-generation for standard-cell ASIC designs

Sudbrock, Joachim; **Raik, Jaan; Ubar, Raimund-Johannes;** Kuzmicz, Wieslaw; Pleskacz, Witold A. Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 79-82 : ill <https://ieeexplore.ieee.org/document/1559781>

Improved fault emulation for synchronous sequential circuits

Raik, Jaan; Ellervee, Peeter; Tihomirov, Valentin; Ubar, Raimund-Johannes Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 72-78 : ill

Power-constrained hybrid BIST test scheduling in an abort-on-first-fail test environment

He, Zhiyuan; **Jervan, Gert;** Peng, Zebo; Eles, Petru Proceedings : DSD'2005 : 8th Euromicro Conference on Digital System Design : Architectures, Methods and Tools : Porto, Portugal, August 30 - September 3, 2005 2005 / p. 83-86 : ill <https://ieeexplore.ieee.org/document/1559782>